

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π -MOS VII)**2SK3669**

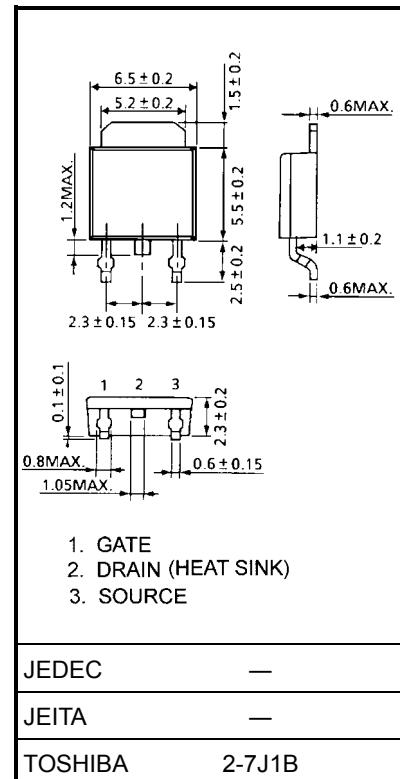
Switching Regulators, for Audio Amplifier and Motor Drive Applications

Unit: mm

- Low drain-source ON resistance: $R_{DS(ON)} = 95 \text{ m}\Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 6 \text{ S}$ (typ.)
- Low leakage current: $I_{DSS} = 100 \mu\text{A}$ (max) ($V_{DS} = 100 \text{ V}$)
- Enhancement-mode: $V_{th} = 3.0 \text{ to } 5.0 \text{ V}$ ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics	Symbol	Rating	Unit
Drain-source voltage	V_{DSS}	100	V
Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$)	V_{DGR}	100	V
Gate-source voltage	V_{GSS}	± 20	V
Drain current	DC (Note 1)	I_D	10
	Pulse ($t_w \leq 10 \text{ ms}$) (Note 1)	I_{DP}	15
	Pulse ($t_w \leq 1 \text{ ms}$) (Note 1)	IDP	28
Drain power dissipation ($T_c = 25^\circ\text{C}$)	P_D	20	W
Single pulse avalanche energy (Note 2)	E_{AS}	280	mJ
Avalanche current	I_{AR}	10	A
Repetitive avalanche energy (Note 3)	E_{AR}	2	mJ
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	-55 to 150	$^\circ\text{C}$



Weight: 0.36 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th(ch-c)}$	6.25	$^\circ\text{C}/\text{W}$
Thermal resistance, channel to ambient	$R_{th(ch-a)}$	125	$^\circ\text{C}/\text{W}$

Note 1: Please use devices on condition that the channel temperature is below 150°C .

Note 2: $V_{DD} = 50 \text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 3.44 \text{ mH}$, $I_{AR} = 10 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device. Please handle with caution.

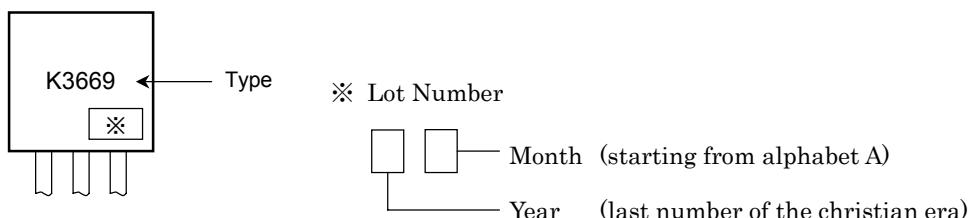
Electrical Characteristics ($T_a = 25^\circ C$)

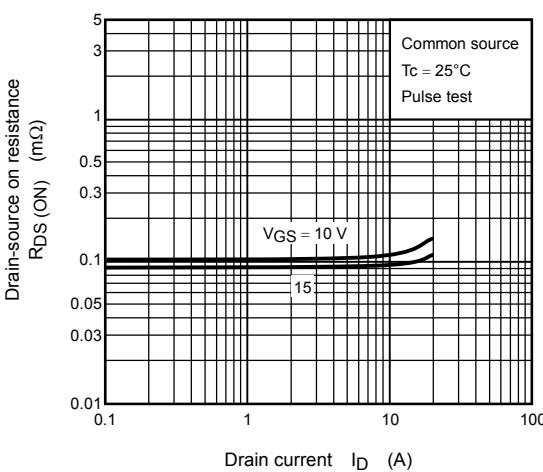
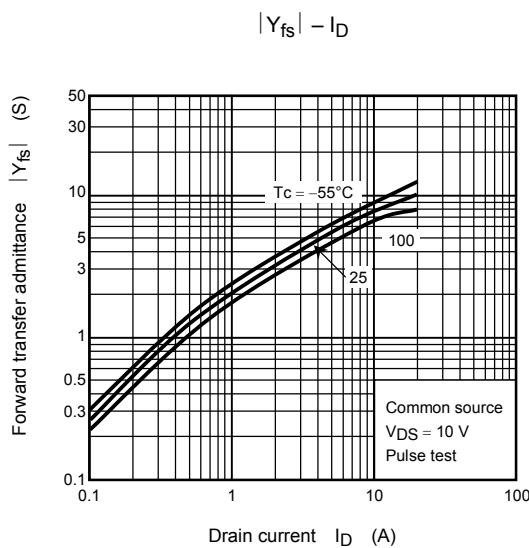
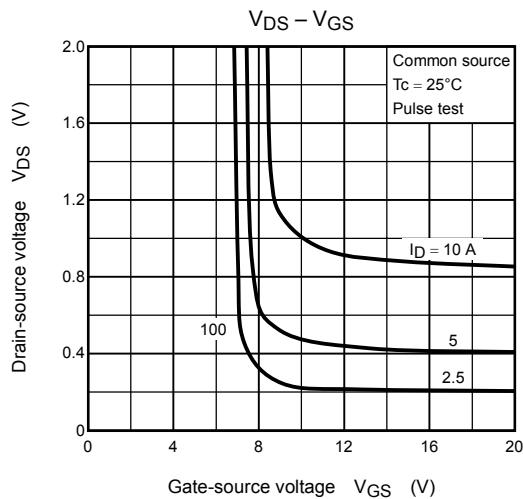
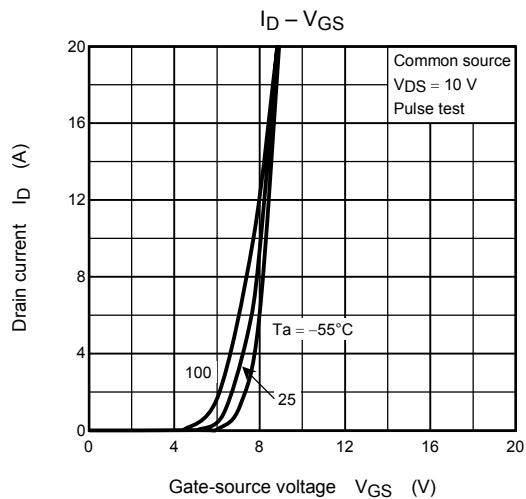
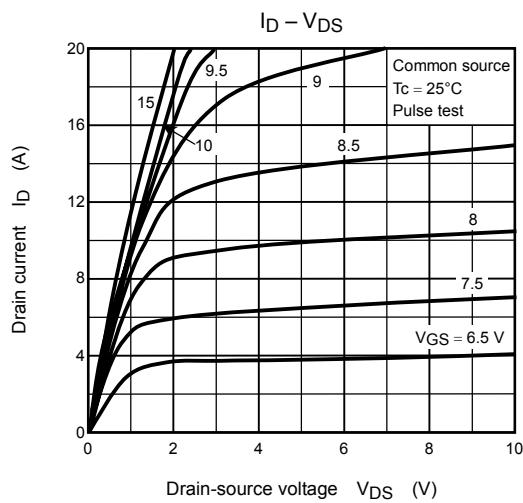
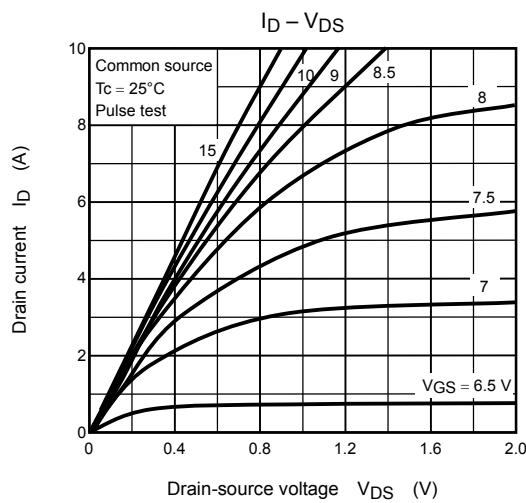
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	I_{GSS}	$V_{GS} = \pm 16 V, V_{DS} = 0 V$	—	—	± 100	nA
Drain cut-off current	I_{DSS}	$V_{DS} = 100 V, V_{GS} = 0 V$	—	—	100	μA
Drain-source breakdown voltage	$V_{(BR) DSS}$	$I_D = 10 mA, V_{GS} = 0 V$	100	—	—	V
Gate threshold voltage	V_{th}	$V_{DS} = 10 V, I_D = 1 mA$	3.0	—	5.0	V
Drain-source ON resistance	$R_{DS (ON)}$	$V_{GS} = 10 V, I_D = 5 A$	—	95	125	$m\Omega$
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = 10 V, I_D = 5 A$	3	6	—	S
Input capacitance	C_{iss}	$V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz$	—	480	—	pF
Reverse transfer capacitance	C_{rss}		—	9	—	
Output capacitance	C_{oss}		—	220	—	
Switching time	Rise time	t_r	 V_{GS} 10 V V_{GS} 0 V $I_D = 10 A$ $V_{DD} \approx 50 V$ $Duty \leq 1\%, t_w = 10 \mu s$	—	2	—
	Turn-on time	t_{on}		—	12	—
	Fall time	t_f		—	2	—
	Turn-off time	t_{off}		—	12	—
Total gate charge (gate-source plus gate-drain)	Q_g	$V_{DD} \approx 80 V, V_{GS} = 10 V, I_D = 10 A$	—	8.0	—	nC
Gate-source charge	Q_{gs}		—	5.6	—	
Gate-drain ("miller") charge	Q_{gd}		—	2.4	—	

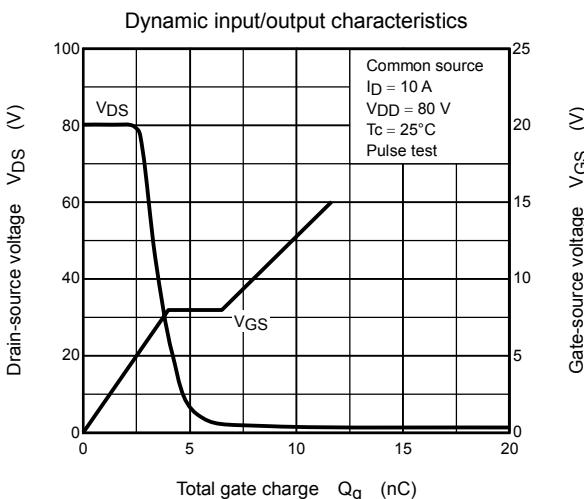
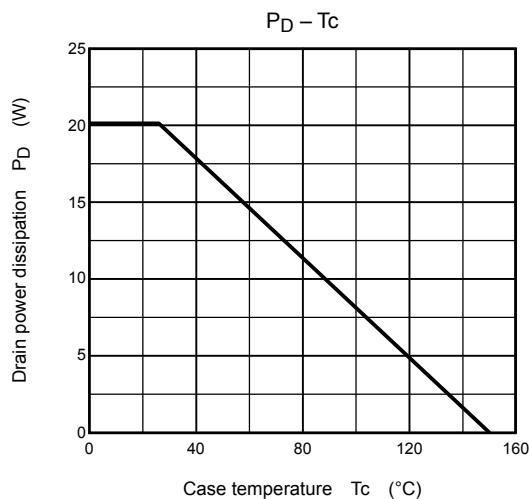
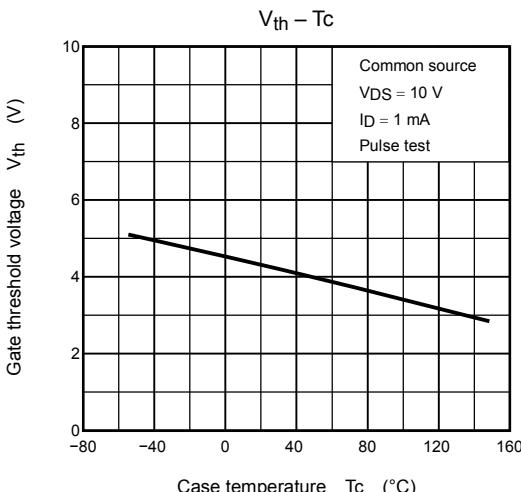
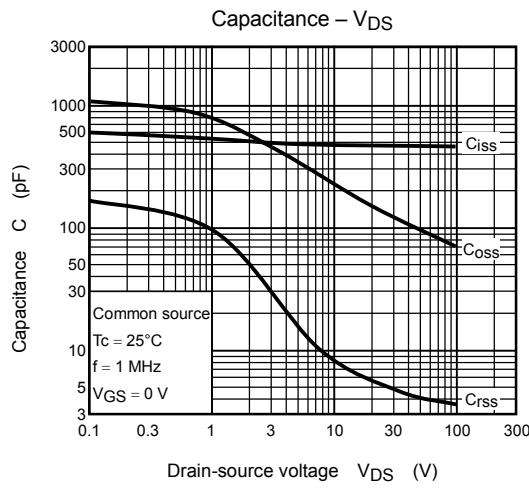
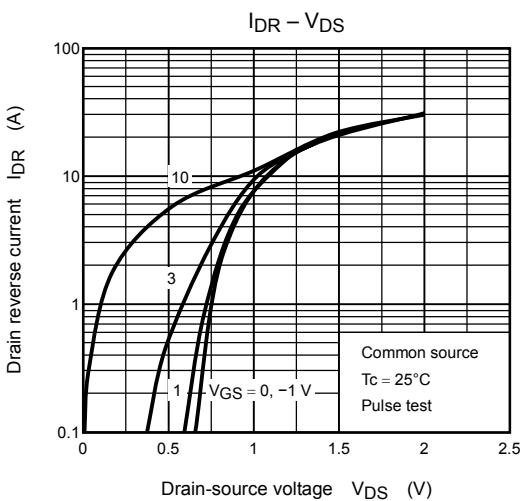
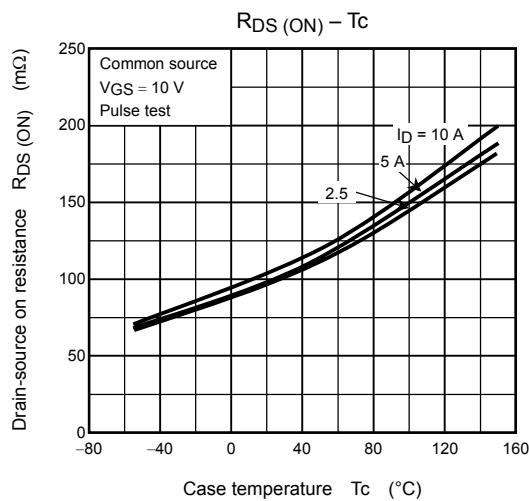
Source-Drain Diode Ratings and Characteristics ($T_a = 25^\circ C$)

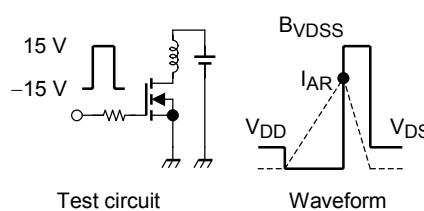
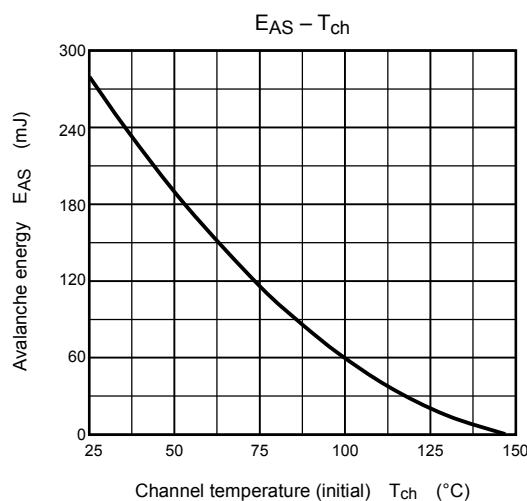
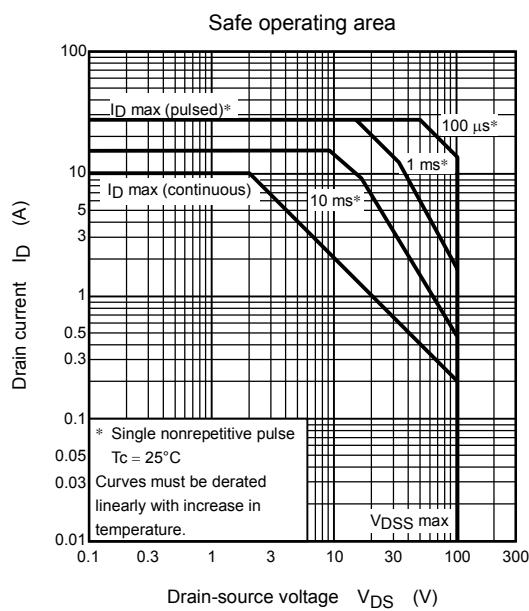
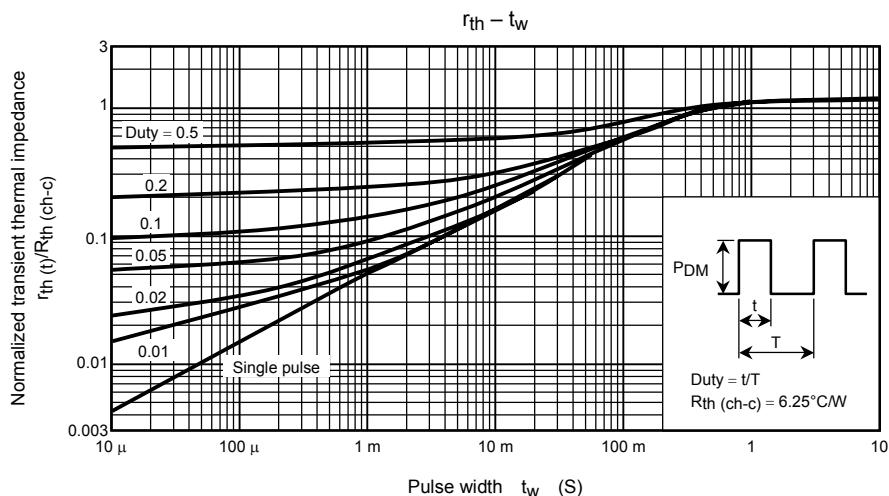
Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	—	—	—	10	A
Pulse drain reverse current ($t_w \leq 10 ms$) (Note 1)	I_{DRP}	—	—	—	15	A
Pulse drain reverse current ($t_w \leq 1 ms$) (Note 1)	I_{DRP}	—	—	—	28	A
Forward voltage (diode)	V_{DS2F}	$I_{DR1} = 10 A, V_{GS} = 0 V$	—	—	-1.7	V
Reverse recovery time	t_{rr}	$I_{DR} = 10 A, V_{GS} = 0 V,$ $dI_{DR}/dt = 50 A/\mu s$	—	65	—	ns
Reverse recovery charge	Q_{rr}		—	90	—	nC

Marking









$$R_G = 25 \Omega$$

$$V_{DD} = 50 \text{ V}, L = 3.44 \text{ mH}$$

$$E_{AS} = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{B_{VDSS}}{B_{VDSS} - V_{DD}} \right)$$

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